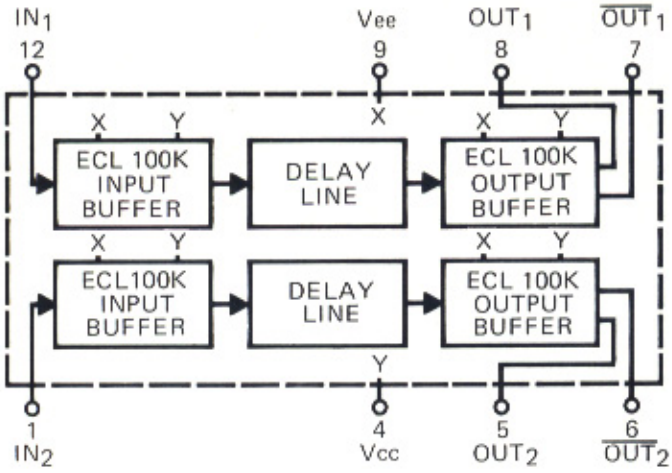
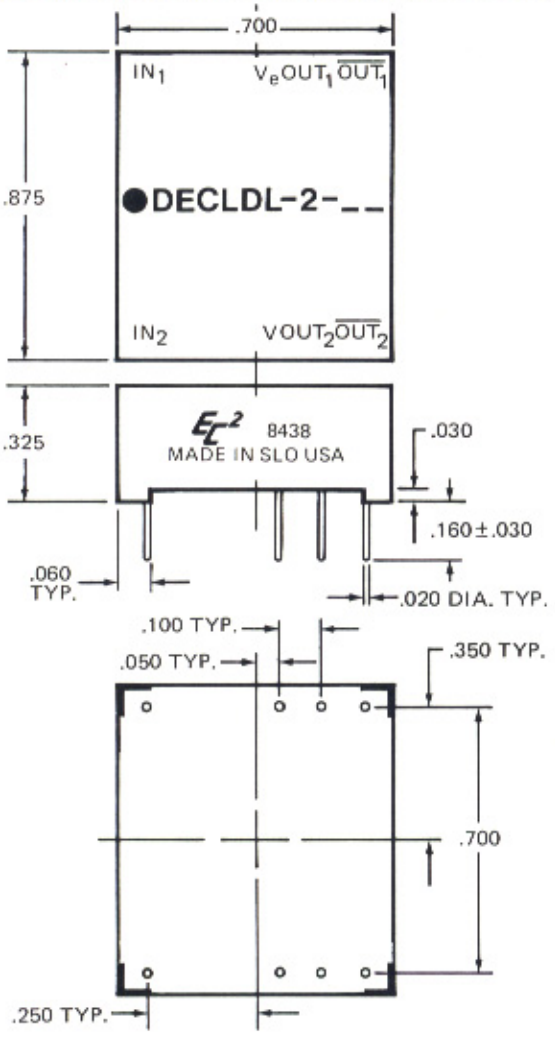
BLOCK DIAGRAM IS SHOWN BELOW



MECHANICAL DETAIL IS SHOWN BELOW



TEST CONDITONS

1. All measurements are made at 25°C.
2. Vee supply voltage is maintained at −4.5V DC.
3. All units are tested using a positive input pulse provided by a standard open emitter ECL 100K gate. The input and output utilizes a 50 ohm pull-down resistor to −2V; the output is also loaded with one ECL 100K gate.

ϕ4. Input pulse width used is 5 to 10ns longer than full delay of module under test; spacing between pulses (falling edge to rising edge) is three times the pulse width used.

OPERATING SPECIFICATIONS

* Supply voltage:	−4.5V ±5% to Vee
Supply current:	155ma typical
Logic 1 Input at 25°C:	
Voltage	−1.165 min.
Current	350ua max.
Logic 0 Input at 25°C:	
Voltage	−1.475V max.
Current	.5ua min.
Logic 1 Output at 25°C:	−1.025 min.
Logic 0 Output at 25°C:	−1.620 max.
Operating temperature range:	0 to +85°C
Storage temperature:	−55 to +125°C

* Delays increase or decrease less than .5% for a respective increase or decrease of 5% in supply voltage.

PART NUMBER TABLE

ϕ DELAYS AND TOLERANCES (in ns)			
PART NO.	OUTPUT	PART NO.	OUTPUT
DECLDL-2-2	2±.2	DECLDL-2-10	10±1
DECLDL-2-2.5	2.5±.2	DECLDL-2-10.5	10.5±1
DECLDL-2-3	3±.3	DECLDL-2-11	11±1
DECLDL-2-3.5	3.5±.3	DECLDL-2-11.5	11.5±1
DECLDL-2-4	4±.4	DECLDL-2-12	12±1
DECLDL-2-4.5	4.5±.4	DECLDL-2-12.5	12.5±1
DECLDL-2-5	5±.5	DECLDL-2-13	13±1
DECLDL-2-5.5	5.5±.5	DECLDL-2-13.5	13.5±1
DECLDL-2-6	6±.6	DECLDL-2-14	14±1
DECLDL-2-6.5	6.5±.6	DECLDL-2-14.5	14.5±1
DECLDL-2-7	7±.7	DECLDL-2-15	15±1
DECLDL-2-7.5	7.5±.7	DECLDL-2-16	16±1
DECLDL-2-8	8±.8	DECLDL-2-17	17±1
DECLDL-2-8.5	8.5±.8	DECLDL-2-18	18±1
DECLDL-2-9	9±.9	DECLDL-2-19	19±1
DECLDL-2-9.5	9.5±.9	DECLDL-2-20	20±1

ϕ All modules can be operated with a minimum input pulse width of 100% of full delay and pulse period approaching square wave; since delay accuracies may be somewhat degraded, it is suggested that the module be evaluated under the intended specific operating conditions. Special modules can be readily manufactured to improve accuracies and/or provide customer specified random delay times for specific applications.